

# Smartphones - From vacuum tubes to integrated circuits

Nik Dennler

December 12, 2016

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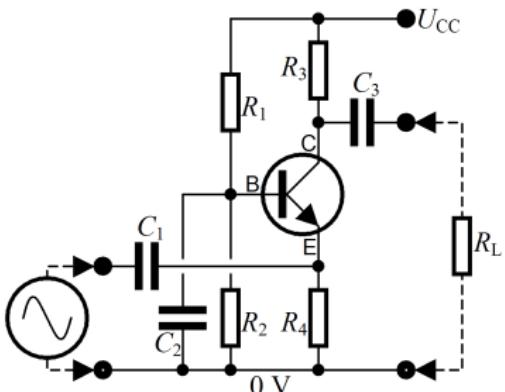


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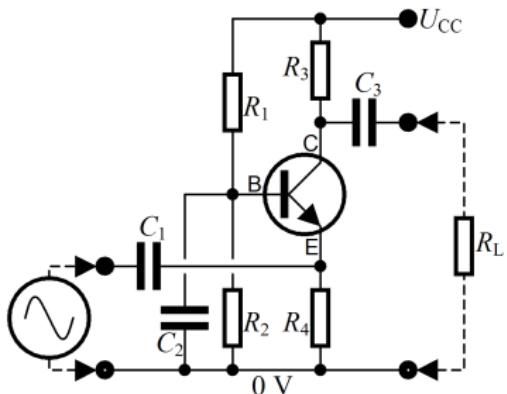


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# Binary Representation

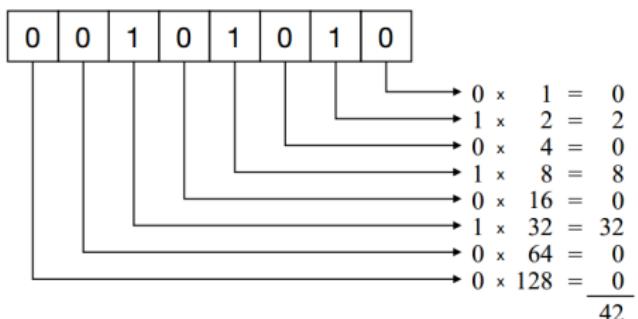


Figure : <http://binarynumbersa.blogspot.ch/2012/02/representation-of-binary-numbers.html>



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# Bool Algebra and logical circuits

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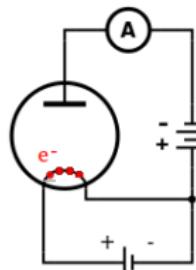
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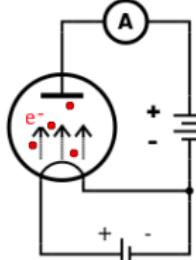
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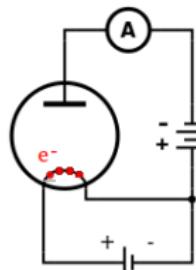
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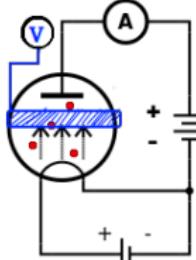
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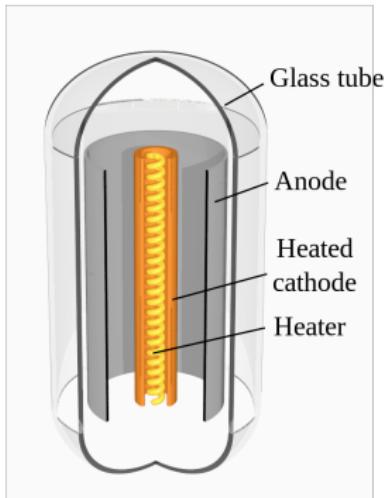


Figure : <https://en.wikipedia.org/wiki/.../media/File:Diode.svg>

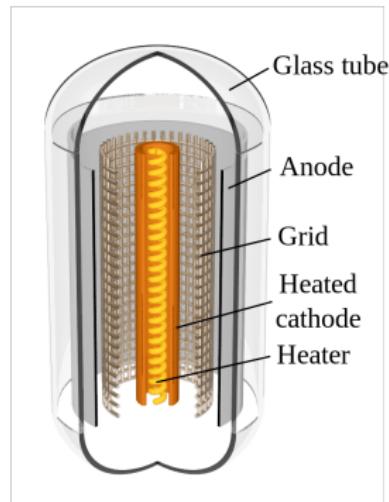


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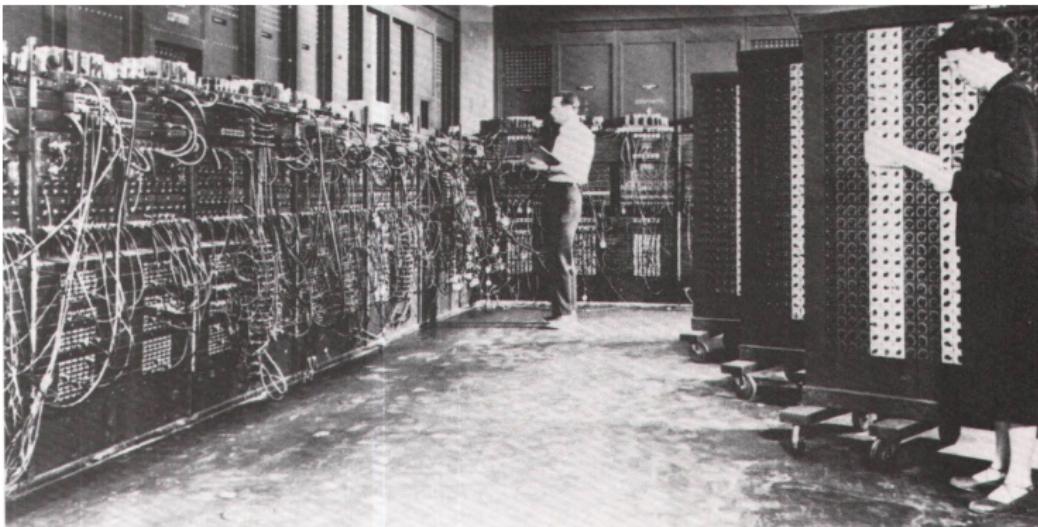


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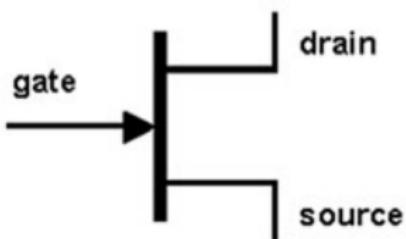


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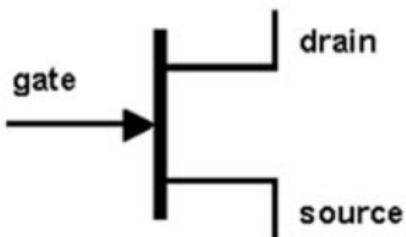


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# Logic gates & Integrated Circuits

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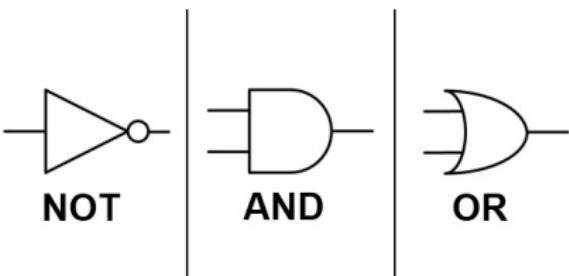


Figure: <http://www.mibb-design.com>

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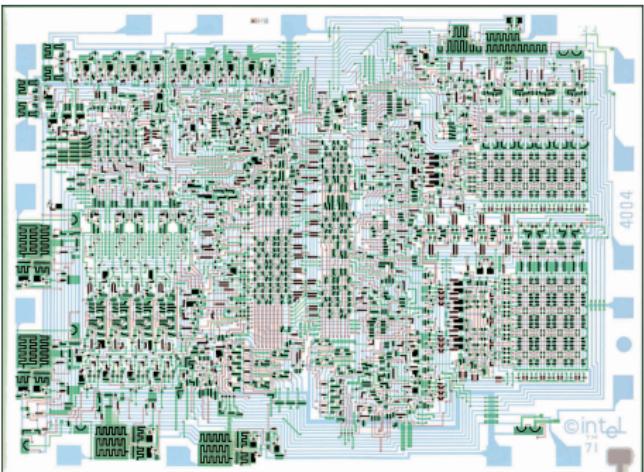


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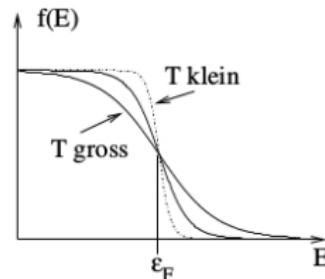
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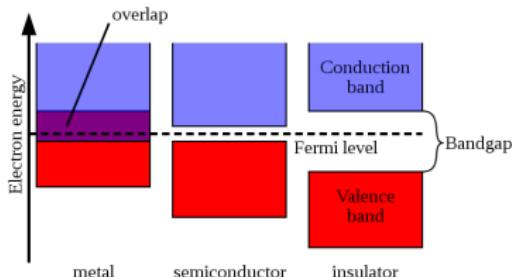


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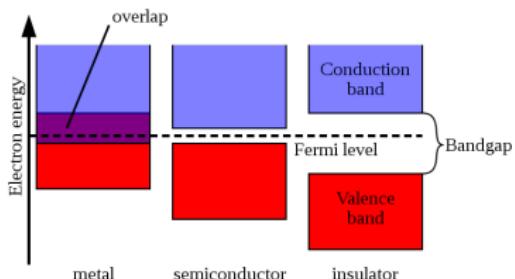


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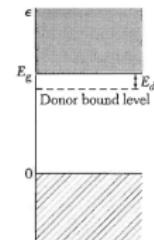
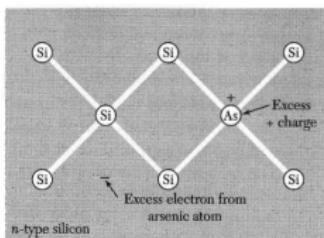


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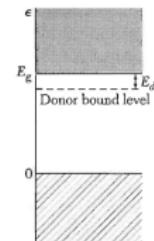
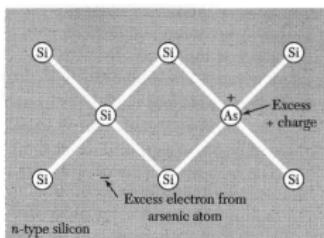


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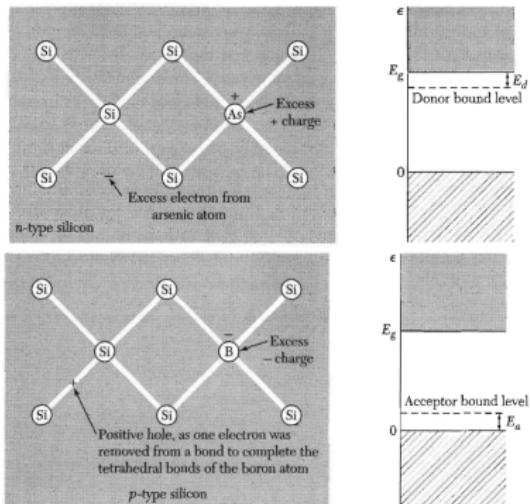


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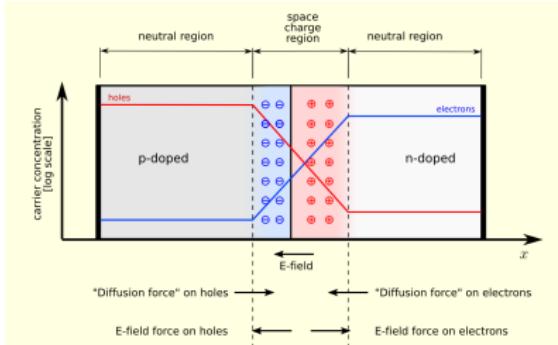


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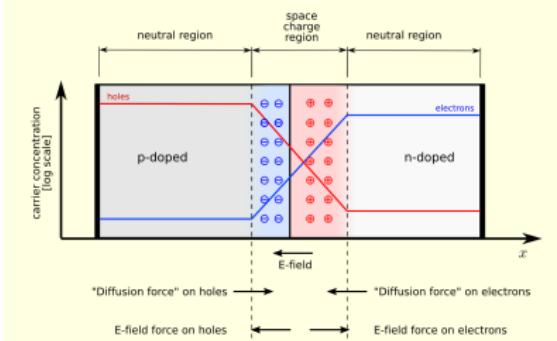


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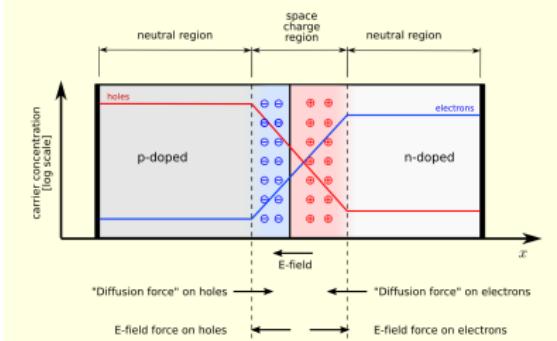


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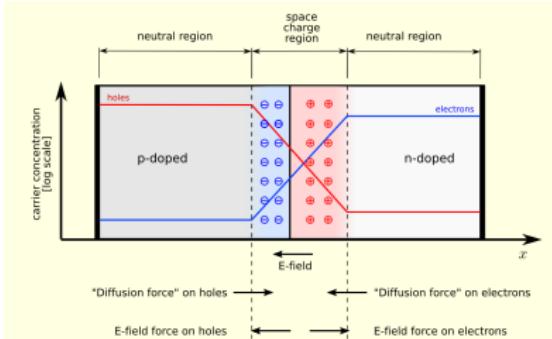


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- Emitter, Base, Collector

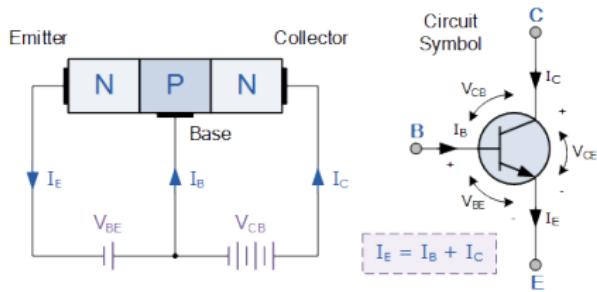


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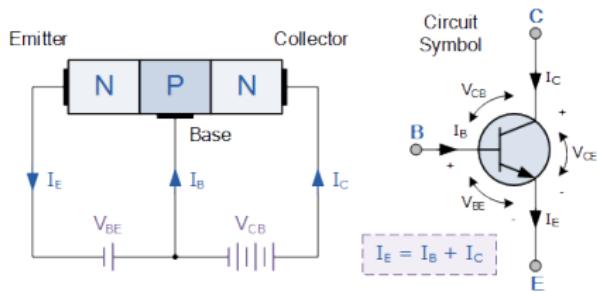


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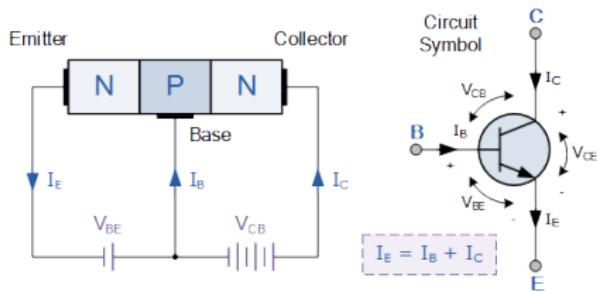


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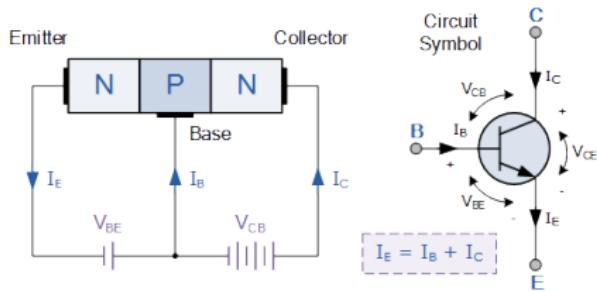


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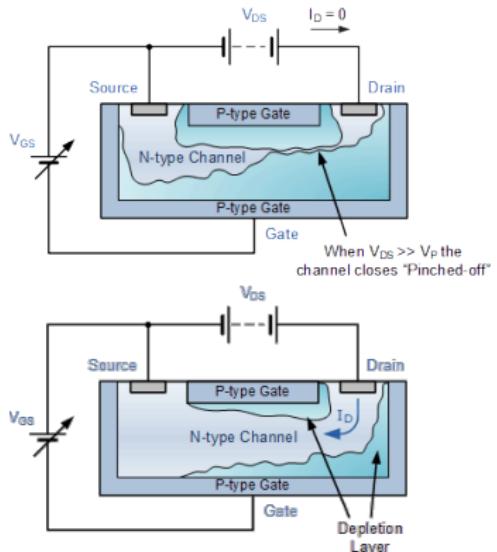


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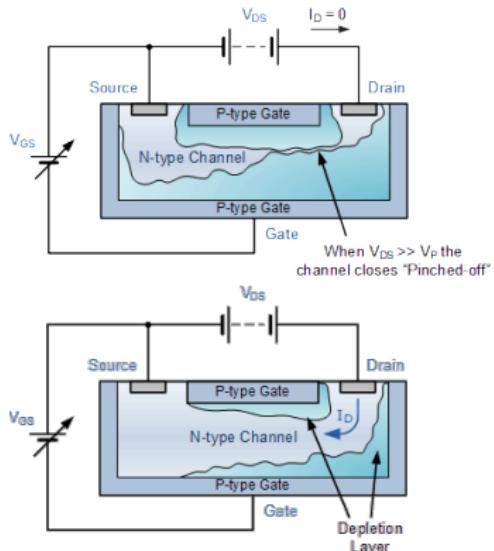


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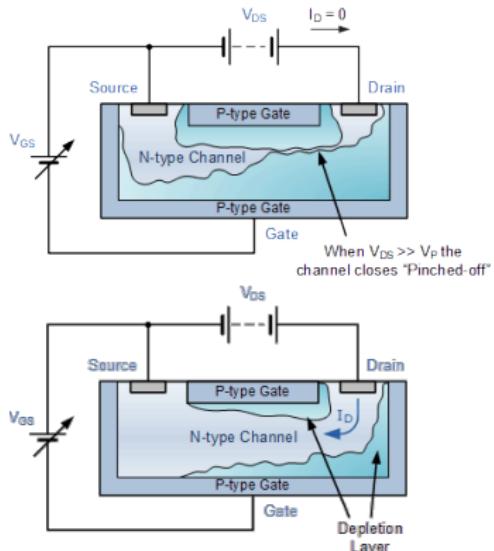


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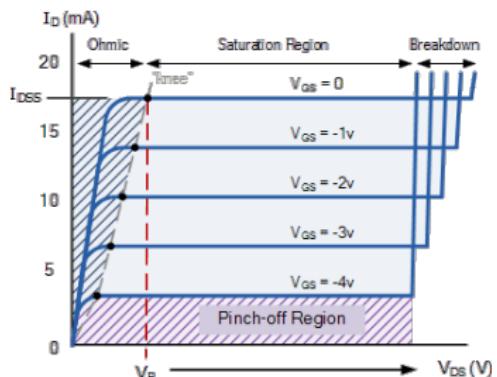


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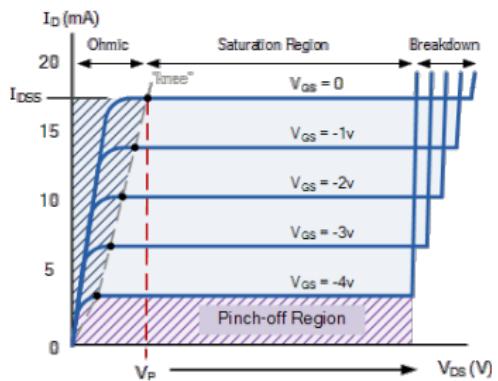


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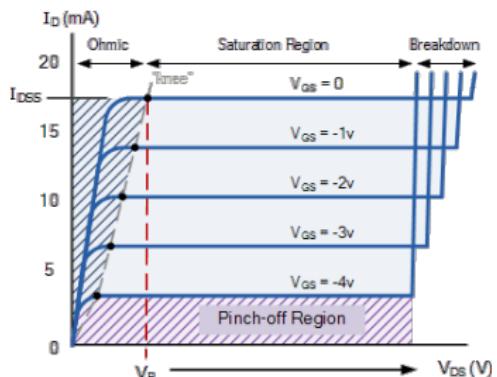


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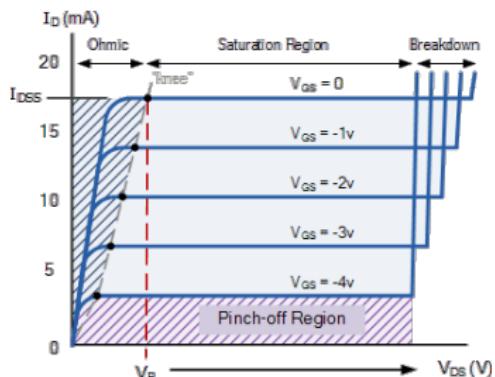


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# MOSFET

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- Insulating layer raises the input resistance of the MOSFET and prevents any channel-gate-current

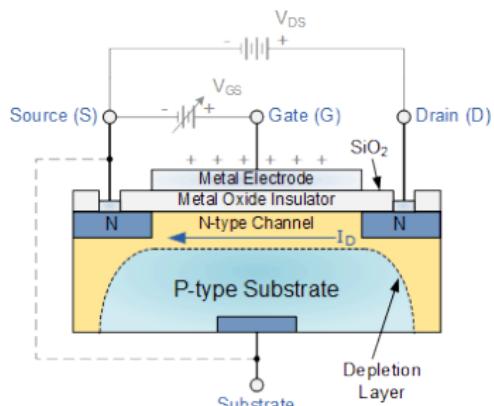


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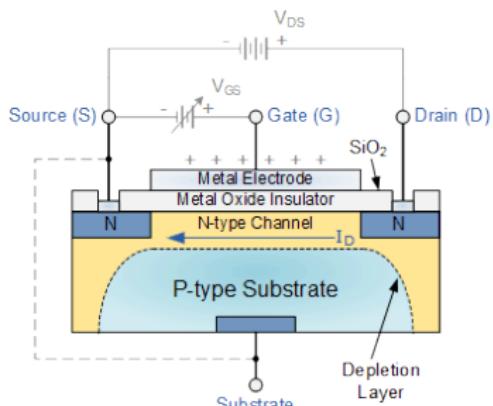
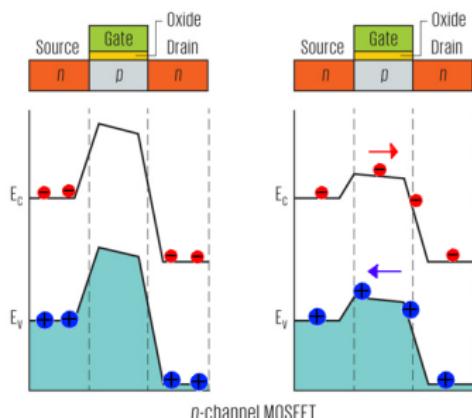


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# MOSFET

- Electrons in conducting band, holes in valence band
- In Off-state can charge carriers not pass big potential wall
- In On-state the potential wall is lowered and charges can pass



# Differences, advantages and disadvantages of BJTs and MOSFETs

BJT	MOSFET	
emitter, collector, base	gate, source, channel, drain	
electron and hole state conduction	either electron or hole state conduction	
controlled by current	controlled by voltage	
less complex	vulnerable to electrostatic damage during installation	

# Differences, advantages and disadvantages of BJTs and MOSFETs

BJT	MOSFET
	much less leak current
	no additional power draw after the gate is opened or closed
	more resistant against radiation

→ Nowadays, if in digital and analog circuits, MOSFETs are more commonly used than BJTs.

# What do we demand of a transistor?

- Speed: high electron current from source to drain

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# Ultrathin Body Silicon on Insulator (UTB-SOI)

- Thin layer of buried oxide on top of base silicon
- Very thin channel

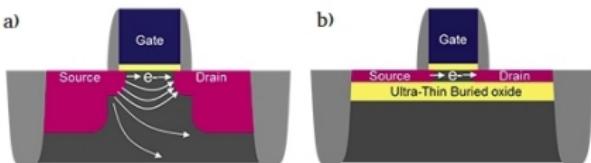


Figure: <http://www.st.com/.../FD-SOI/learn-more-about-fd-soi.html>

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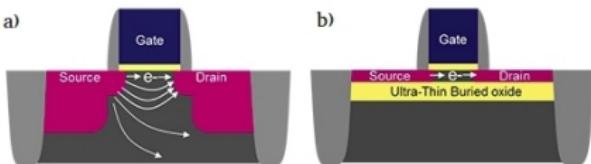


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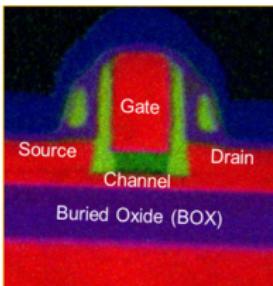


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## From 2D to 3D: FinFET

- 3D architecture brings the gate closer to the drain
- Conducting channel that rises above insulator level, creating a fin-shaped gate electrode

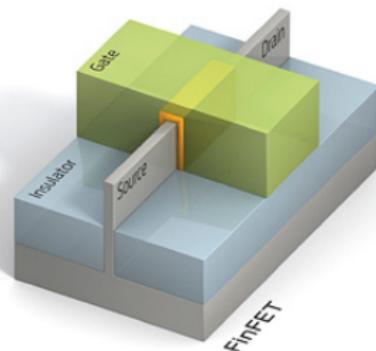


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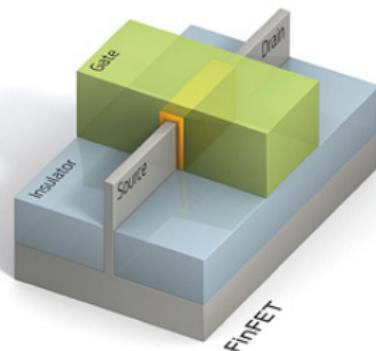


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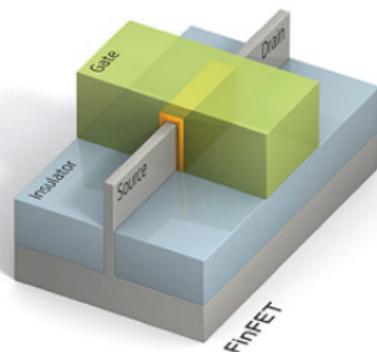


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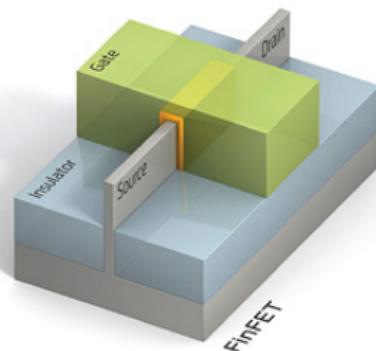


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# Moore's Law

- Goal: making the smallest transistor while staying in the cost optimum
- *Moore's Law* (1965): The transistor count on an integrated circuit will double every two years

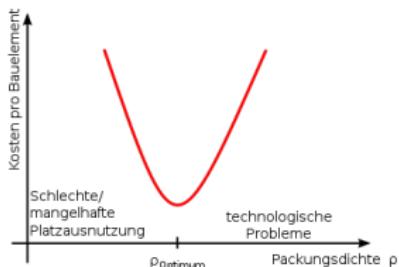


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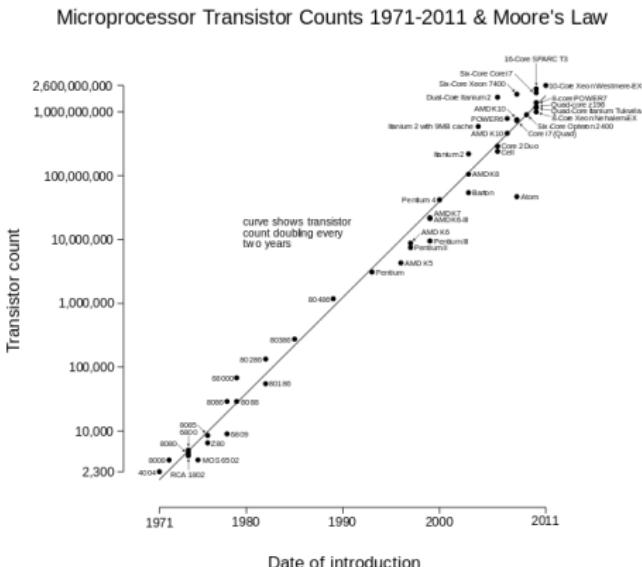
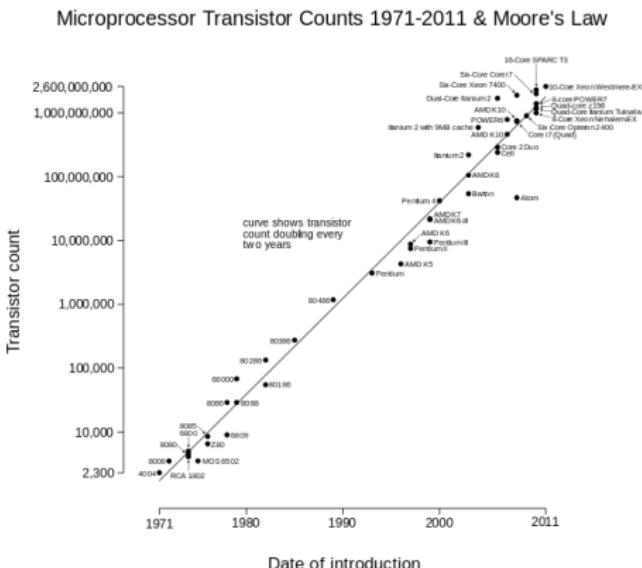


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# Tunneling probability approximation (WKB)

- Time independent Schroedinger equation

$$-\frac{\hbar}{2m^*} \frac{d^2\Psi}{dx^2} + (V(x) - E)\Psi = 0,$$

has general solution  $\Psi(x) = A e^{kx} + B e^{-kx}$

- Assume potential is space-independent between  $x$  and  $x + dx$ :

$$\Psi_{\rightarrow}(x+dx) = \Psi(x) \exp(-k dx), \text{ where } k = \frac{\sqrt{2m^*[V(x) - E]}}{\hbar}$$

- Plug in and get WKB approximation integral:

$$\Psi(L) = \Psi(0) \exp\left(-\int_0^L \frac{\sqrt{2m^*[V(x) - E]}}{\hbar} dx\right)$$

# Tunneling probability approximation (WKB)

- Use a triangular potential barrier:  $V(x) - E = q\Phi_B(1 - \frac{x}{L})$  where  $\Phi_B$  is the barrier height
- Calculate tunnel probability

$$\Gamma_{Tunnel}(L) = \frac{|\Psi(L)|^2}{|\Psi(0)|^2} = \frac{\Psi(L)\Psi(L)^*}{\Psi(0)\Psi(0)^*}$$

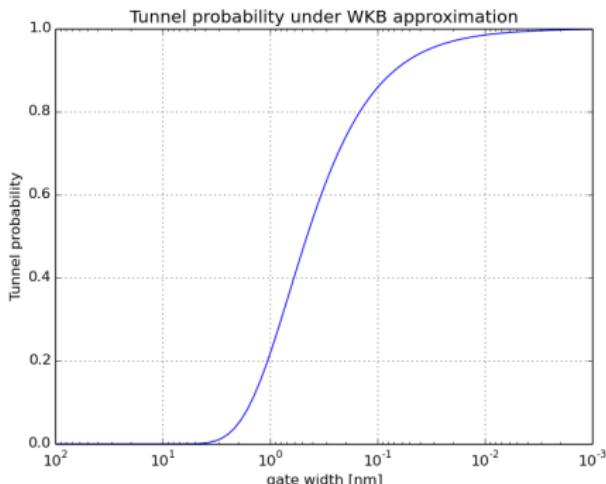
$$= \exp\left(-2 \int_0^L \frac{\sqrt{2m^*q}}{\hbar} \sqrt{\Phi_B\left(1 - \frac{x}{L}\right)} dx\right)$$

$$= \exp\left(-\frac{4}{3} \frac{\sqrt{2m^*q \cdot \Phi_B}}{\hbar} \cdot L\right)$$

# Tunneling probability approximation (WKB)

- For  $q\Phi_B = q(\Phi_{ox} - \chi_{silicon}) = 0.25eV$ , and  $L = 1 \text{ nm}$  we get

$$\Gamma \approx 21.7\%$$



## Possible candidates?

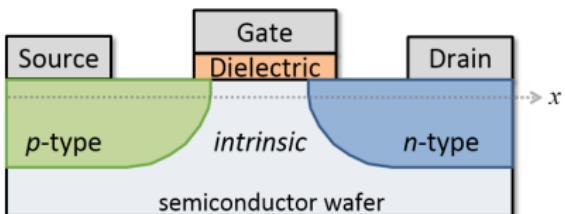
- Tunnel FETS
- Gallium-Arsenide transistors
- Mott insulators
- Organic semiconductors
- Graphene transistors
- Photoemission-based microelectronic devices
- etc.

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# Tunnel Field Effect Transistor (TFET)

- Idea: use quantum tunneling!
- $p$ - $i$  and  $i$ - $n$  junctions are used



# Tunnel Field Effect Transistor (TFET)

- In Off-state, all charge carriers are initially in the valence band
- In On-state, the energy level of the intrinsic area is lowered with gate-voltage, which leads to a narrowing of the tunnel wall.
- The electrons tunnel from valence band to conducting band → current!

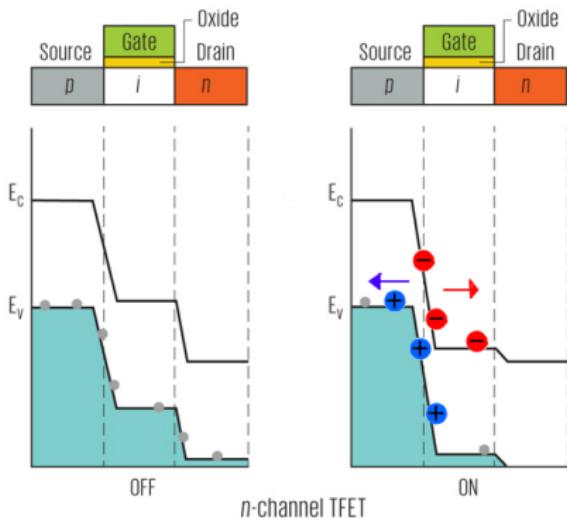


Figure: <http://spectrum.ieee.org/semiconductors>

# Advantages and disadvantages of TFETs

- Much lower barrier thickness necessary ( $\sim 1$  atom)  
→ size could be drastically reduced
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- Much lower barrier thickness necessary ( $\sim 1$  atom)  
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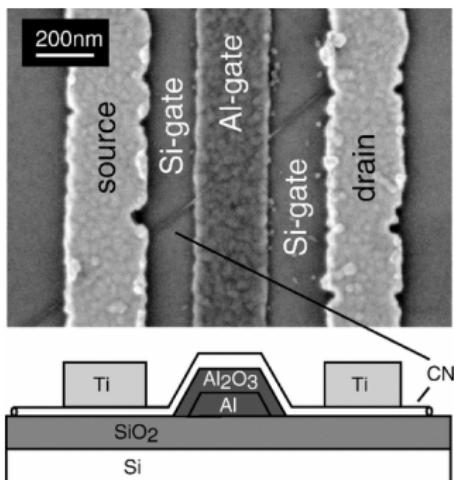


Figure: Appenzeller, J. (2004). PhysicalReviewLetters93(19)

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## Questions?

## Backup Slides

# Bipolar Junction Transistor (BJT)

- Combination of two junction diodes ( $n-p-n$  or  $p-n-p$ )
- Emitter, Base, Collector
- emitter-collector-current is controlled by current on base.
- EB in forward-bias, CE in reverse-bias

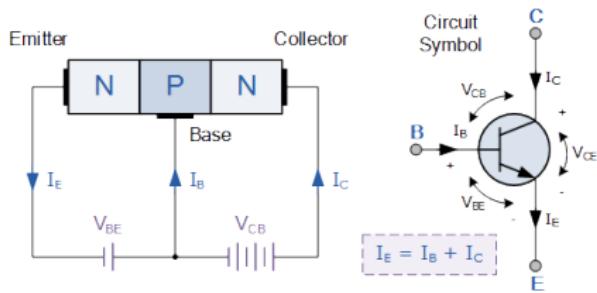


Figure : <http://www.electronics-tutorials.ws>

# Bipolar Junction Transistor (BJT)

- **Cut-Off Region:**  $I_B = 0 \rightarrow$  no CE-current.
- **Saturation Region:**  $I_B > 0$  and  $V_{CE}$  small  $\rightarrow$  large CE-current, no control
- **Active Region:**  $I_B > 0$  and  $V_{CE}$  large  $\rightarrow$  CE-current controlled by base-current

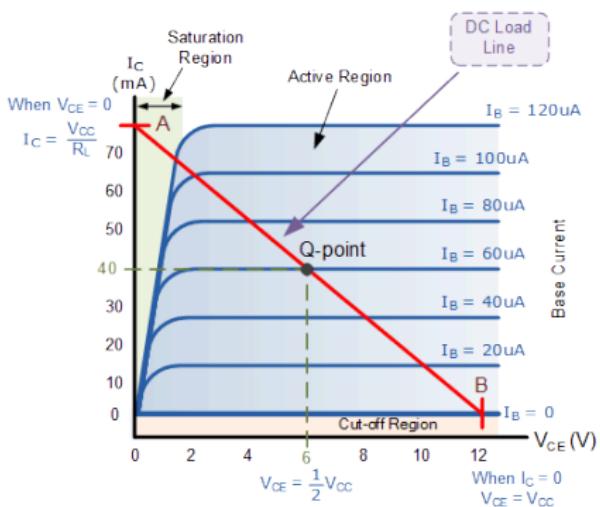
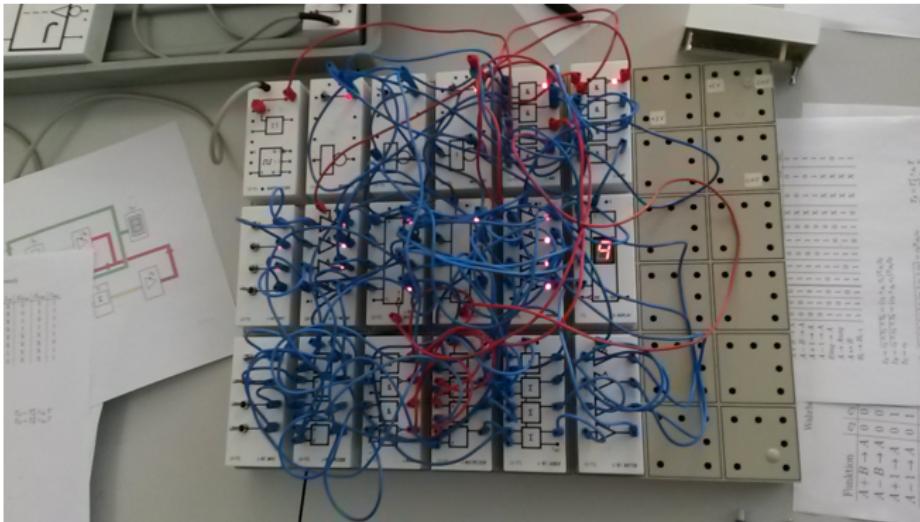


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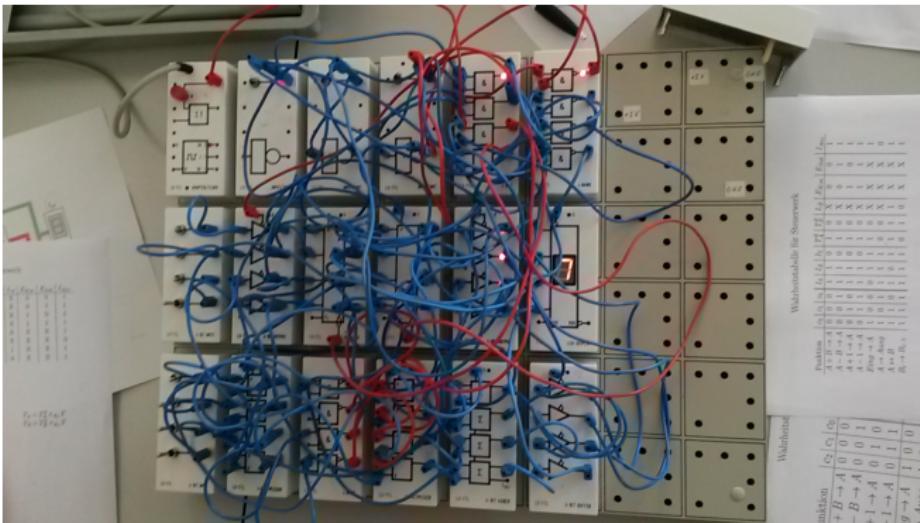
# Manufacturing Process

- ① Create Wafer: Sand  $\xrightarrow{\text{melting}}$  Monocrystalline Silicon Ingot  $\xrightarrow{\text{slicing}}$  Silicon Wafer
- ② Photolithography: Applying photoresist chemical to Wafer → Exposure by masked UV-rays → Removal of soluble photoresist chemicals
- ③ Doping: Patterned photoresist is exposed by a beam of ions (n-type & p-type) → Removal of photoresist chemicals
- ④ Etching: Protect desired parts by hard mask → Photolithography again
- ⑤ Gate Formation: Form temporarily gate with silicon → Fill areas with insulator → Add dielectric → Electroplating

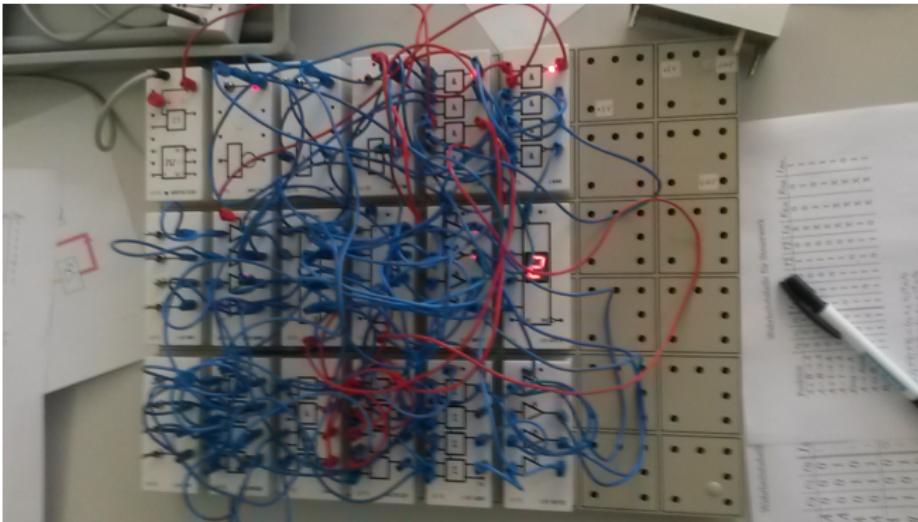
# Logic Gates



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## Logic Gates



# Logic Gates

